

In-Circuit Testing Probes



In-Circuit Testing
Printed Circuit Board Testing



C.C.P. CONTACT PROBES

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C.C.P. Contact Probes Co., Ltd. is a leading global manufacturer of Contact Probes, Pogo Pins, Testprobes, Springloaded Connectors, and Crown Spring Connectors.

In 1986 we began as a specialized provider of test probes and socket auxiliary solutions and slowly expanded our product portfolio in related industries such as electronic components manufacturing. Among our customers are renowned brands like Apple and Amazon and our products are revered by our customers for their exceptional reliability and superior quality.

Our research and development teams are continuously improving our existing products and bringing new innovations to the market to meet the growing demands of our clients. Since 2001 CCP Contact Probes has been a public traded company listed on the Taiwan Stock Exchange. Today CCP has subsidiaries in the United States, China, Germany, India, Japan and Singapore, meeting the needs of our customers around the world.

ABOUT US

Introduction

Selected Customers

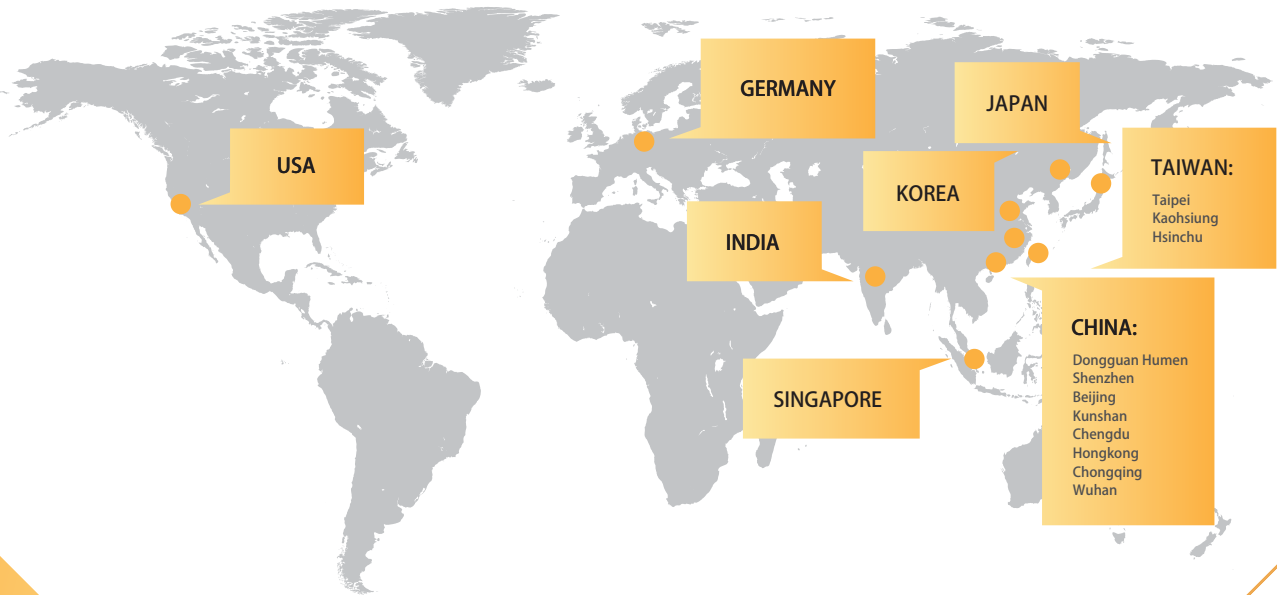
FOXCONN

Google



ADVANTEST

Locations



ABOUT US

History

History

2018

CCP Germany, Singapore & India Established

2016

High Current Connector Product Line

2014

CCP USA Established

2003

Listed on Taiwan Stock Market (TW. 6217))

2002

Commercial Connector Product Line

2001

CCP Dongguan Factory Established

1986

CCP Established/ Testing Product Line

Company Culture



Yearly Home Visit



Employee's Children
Summer Camp



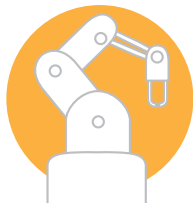
Tuition Subsidy
for Employee's Children

ABOUT US

Advantages



Over 30 Years of Product Development Experience
Servicing Industry-leading Clients

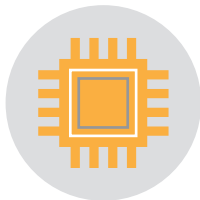


Agile and Flexible Design Process with Self-owned
Turning and Plating Factory



A Proven Track-record of Reliability, an Industry Certified Quality
Management System, and State-of-the-art Production Equipment

Product Lines



Testing
Solutions



Commercial
Connector Solutions



High Current
Connector Solutions



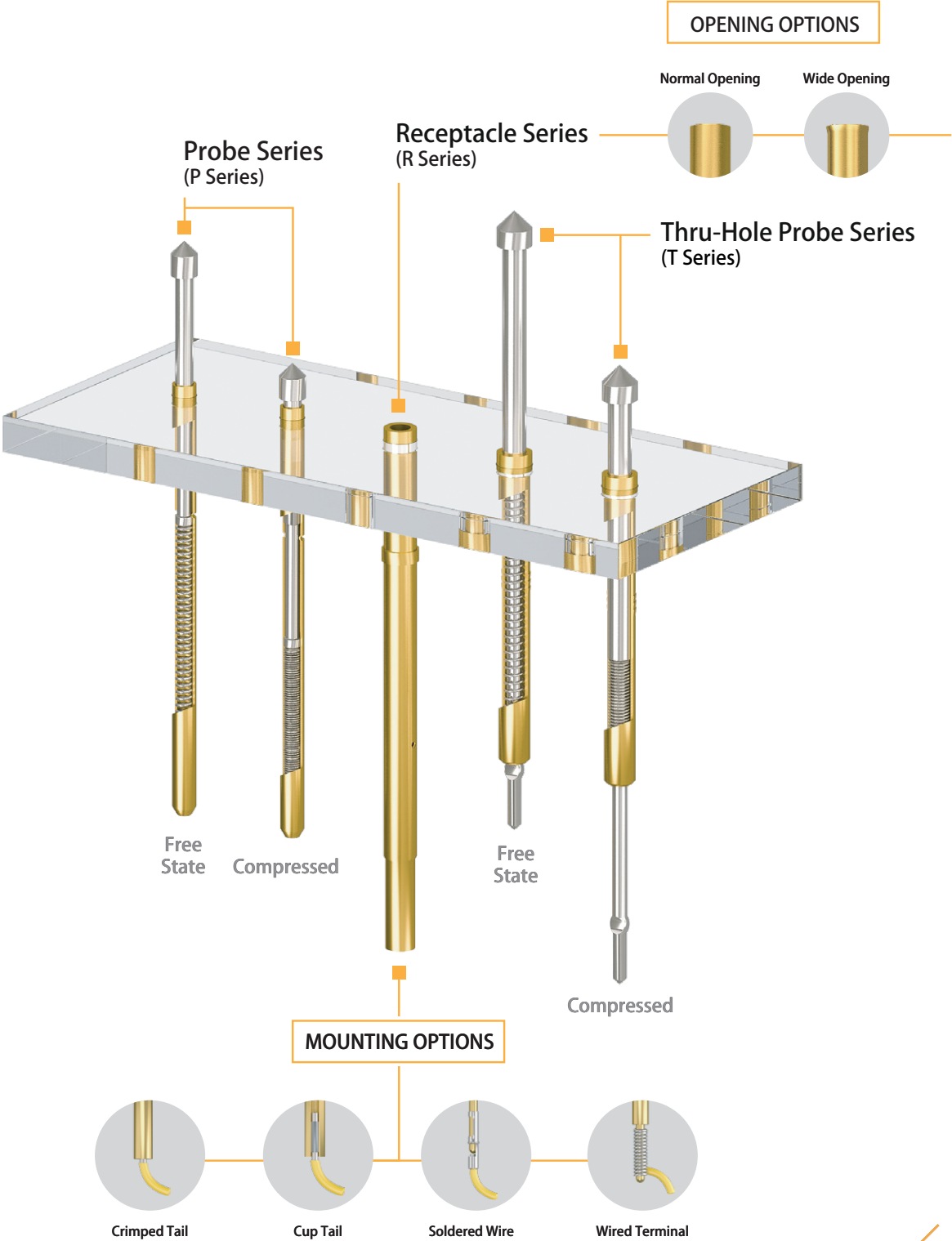
Industrial
Connector Solutions

STRUCTURE

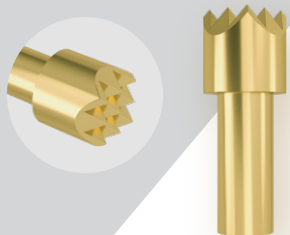


CCP PROBE SERIES

P Series R Series T Series



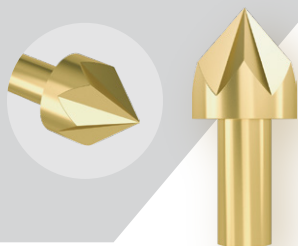
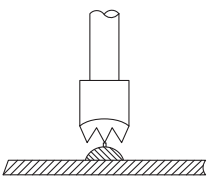
PROBE TIP TYPE



L9

Large 9 Points

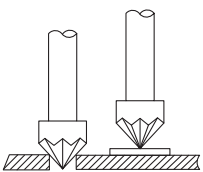
Used to test long leads, terminals, wire wrap posts and pads.



LS

Large Star

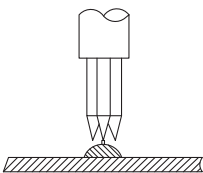
Used to penetrate through holes, pads and gold edge fingers. Will not be contaminated by dust.



LN3

Large Needle 3

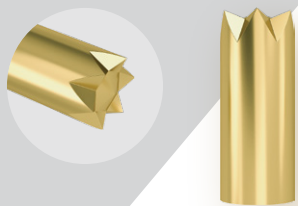
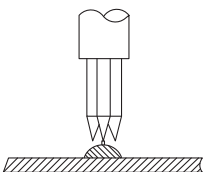
Used to test lands and pads. Needles can penetrate thin layers of oxides or contaminations.



LN7

Large Needle 7

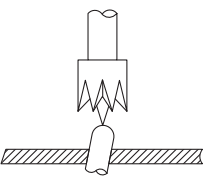
Used to test lands and pads. Needles can penetrate thin layers of oxides or contaminations.



L7

Large 7 Points

Used to test lands, terminals, and wire wrap posts.

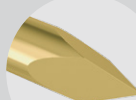
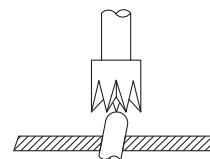




L7M

Large 7 Points with Large Middle Center

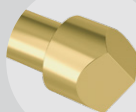
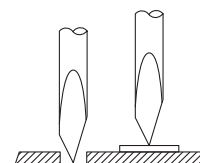
Used to test lands, terminals, and wire wrap posts.



M3C

Medium 3 Side Chiseled

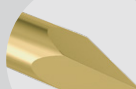
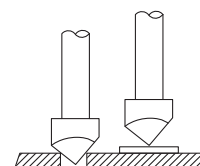
Used to test through holes, pads and gold edge fingers.



L3C

Large 3 Side Chiseled

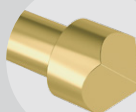
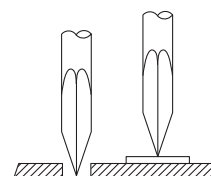
Used to test through holes, pads and gold edge fingers.



M4C

Medium 4 Side Chiseled

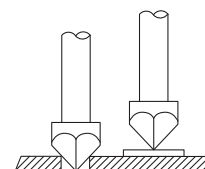
Used to test through holes, pads and gold edge fingers.



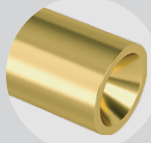
L4C

Large 4 Side Chiseled

Used to test through holes, pads and gold edge fingers.



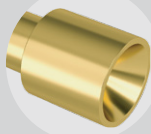
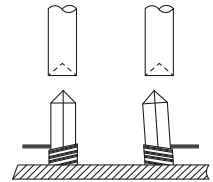
PROBE TIP TYPE



MC

Medium Cup

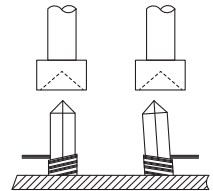
Used to test long leads, terminals and wire wrap posts.



LC

Large Cup

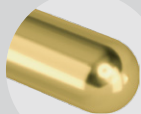
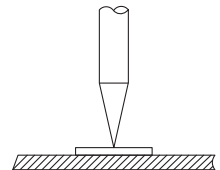
Used to test long leads, terminals and wire wrap posts.



MA

Medium Awl

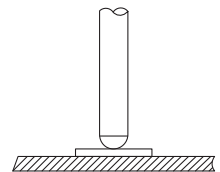
Used to test through holes, pads and gold edge fingers.



MR

Medium Round

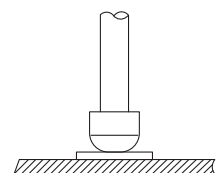
Used to test gold edge fingers and gold pads. Leaves no marks or indentations.



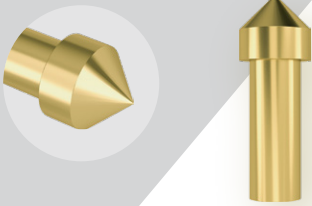
LR

Large Round

Used to test gold edge fingers and gold pads. Leaves no marks or indentations.



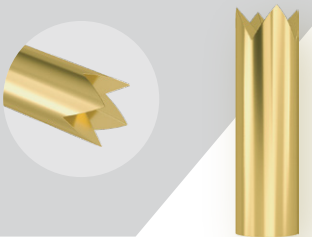
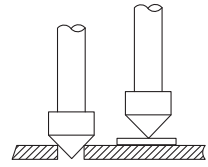
PROBE TIP TYPE



LA

Large Awl

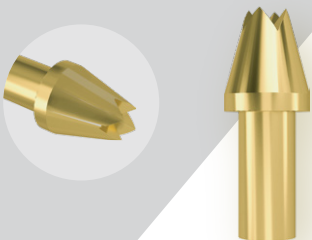
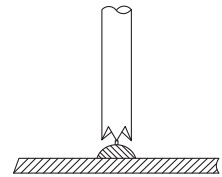
Used to test through holes, pads and gold edge fingers.



M4

Medium 4 Points

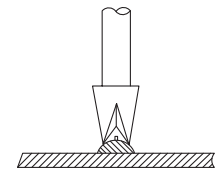
Used to test narrow lands. Will not be contaminated by dust.



L4

Large 4 Points

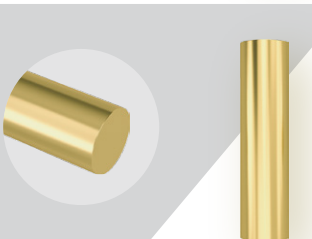
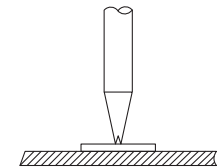
Used to test narrow lands. Will not be contaminated by dust.



S4

Small 4 Points

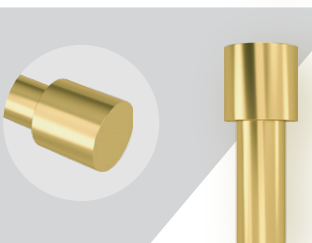
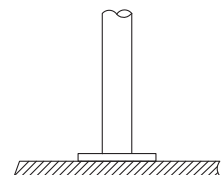
Used to test narrow lands. Will not be contaminated by dust.



MF

Medium Flat

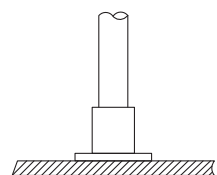
For testing pads and gold edge-fingers. Contact leaves no marks or indentations.



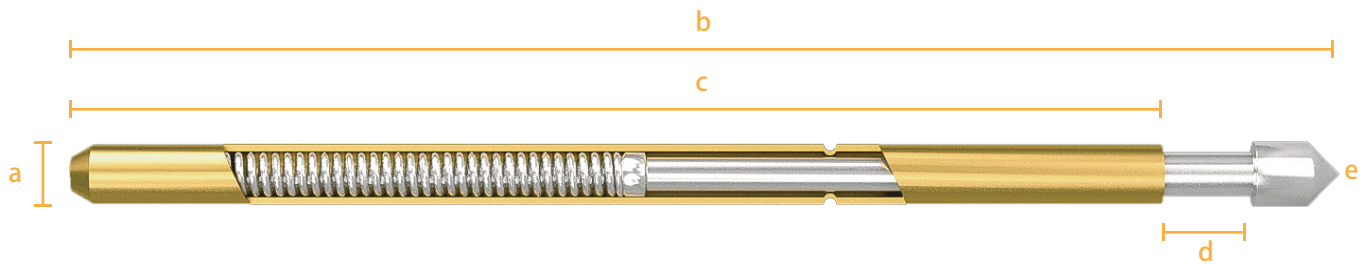
LF

Large Flat

For testing pads and gold edge-fingers. Contact assured leaves no marks or indentations.



P SERIES LIST



Coding Rule:

ICT-P: **a-b-c-d-e**:f-g-h-i

P Series	Dimensions	Materials
----------	------------	-----------

Example:

ICT-P: **020-1150-1000-0150-E** :BC-Au-BR-Au

P Series	Dimensions	Materials
----------	------------	-----------

a	b	c	d
Barrel Diameter in mm	Full Length in mm	Barrel Length in mm	Full Stroke in mm
Recommended Pitch 0.45mm			
0.20	11.50	10.00	01.50
Recommended Pitch 0.50mm			
0.26	12.50	11.00	01.50
Recommended Pitch 0.65mm			
0.30	11.50	10.00	01.50
Recommended Pitch 0.70mm			
0.35	12.50	11.00	01.50
Recommended Pitch 0.80mm			
0.38	12.00	10.00	02.00
0.38	12.50	10.00	02.00
Recommended Pitch 0.90mm			
0.48	12.00	10.00	02.00
0.48	12.60	10.00	02.00
Recommended Pitch 1.00mm			
0.58	15.00	13.00	02.00
0.58	15.60	13.00	02.00
Recommended Pitch 1.27mm			
0.68	16.35	13.00	03.35
0.68	16.55	13.00	02.65
0.68	24.70	18.50	04.20

e

Tip Type
See Tip Type Page

f

Plunger Base
BC: Beryllium Copper
SK4: High Carbon Steel

g

Plunger Plating
Au: Gold
Rh: Rhodium
NA: None

h

Barrel Base
PB: Phosphor Bronze
BR: Brass

i

Barrel Plating
Au: Gold

P SERIES LIST

a	b	c	d
Barrel Diameter in mm	Full Length in mm	Barrel Length in mm	Full Stroke in mm
Recommended Pitch 1.90 mm			
1.01	16.35	13.00	03.35
1.01	17.04	13.00	02.54
1.01	24.20	18.50	04.20
1.01	33.30	25.00	06.30
1.01	38.30	25.00	06.30
Recommended Pitch 2.54 mm			
1.36	23.50	18.50	03.00
1.36	24.70	18.50	04.20
1.36	33.30	25.00	06.30
1.36	38.30	25.00	06.30
1.37	09.70	07.50	02.20
1.37	10.00	07.50	01.50
Recommended Pitch 3.17 mm			
2.00	33.35	25.00	06.35
Recommended Pitch 3.97mm			
2.36	34.10	25.00	06.60

e
Tip Type
See Tip Type Page

f
Plunger Base
BC: Beryllium Copper
SK4:High Carbon Steel

g
Plunger Plating
Au: Gold
Rh: Rhodium
NA: None

h
Barrel Base
PB: Phosphor Bronze
BR: Brass

i
Barrel Plating
Au: Gold

R SERIES LIST



Coding Rule:

ICT-R:**a-b-c-d-e:f-g**

R Series

Dimensions

Materials

Example:

ICT-R:**020-032-0900-00-e:g-h**

R Series

Dimensions

Materials

a	b	c	d
Probe Barrel Diameter in mm	Receptacle Diameter in mm	Probe Holding Length in mm	Collar Distance in mm
Recommended Pitch 0.45mm			
0.20	0.32	09.00	-
Recommended Pitch 0.50mm			
0.26	0.35	10.30	-
Recommended Pitch 0.65mm			
0.30	0.40	09.00	-
Recommended Pitch 0.70mm			
0.35	0.43	10.00	-
0.35	0.45	10.00	-
Recommended Pitch 0.80mm			
0.38	0.53	09.00	-
Recommended Pitch 0.90mm			
0.48	0.62	09.00	-
Recommended Pitch 1.00mm			
0.58	0.72	12.00	-
Recommended Pitch 1.27mm			
0.68	0.86	12.75	-
0.68	0.86	12.75	2.5
0.68	0.86	18.50	-
0.68	0.86	18.50	2.5

e

- Tail Type
- N: No Tail
 - C: Cup Tail
 - W9: Square Tail for Wire Wrapping Tail Length 9mm
 - T5: Round Tail for Crimped Terminal Tail Length 5mm
 - S: Soldered Wire

f

- Receptacle Base
- PB: Phosphor Bronze
 - BR: Brass

g

- Receptacle Plating
- Au: Gold

R SERIES LIST

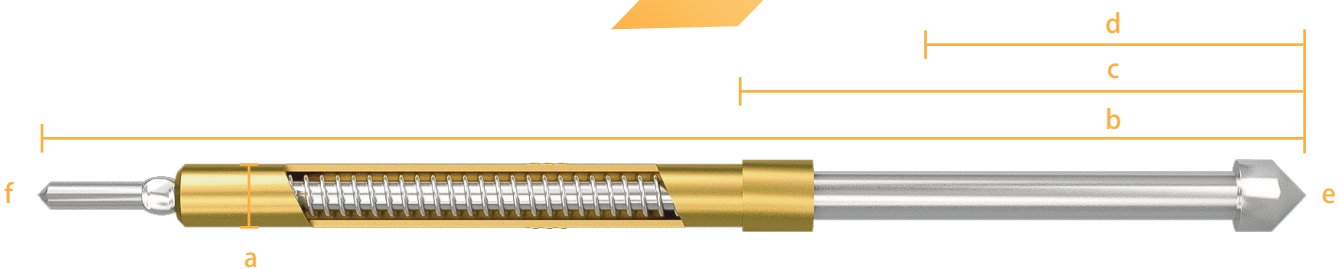
a	b	c	d
Probe Barrel Diameter in mm	Receptacle Diameter in mm	Probe Holding Length in mm	Collar Distance in mm
Recommended Pitch 1.27mm			
1.01	1.31	12.70	-
1.01	1.31	12.70	4.0
1.01	1.31	12.70	2.5
1.01	1.31	18.50	
1.01	1.31	18.50	2.5
1.01	1.31	18.50	4.0
1.01	1.31	25.00	-
1.01	1.31	25.00	7.5
Recommended Pitch 2.54mm			
1.36	1.66	18.50	-
1.36	1.66	18.50	2.5
1.36	1.66	18.50	5.5
1.36	1.66	25.00	-
1.36	1.66	25.00	2.5
1.36	1.66	25.00	5.0
1.36	1.66	25.00	7.5
1.37	1.66	07.50	2.5
1.37	1.66	07.50	-
Recommended Pitch 3.17mm			
2.00	2.36	25.00	-
2.00	2.36	25.00	7.5
Recommended Pitch 3.97mm			
2.36	2.69	24.70	-
2.36	2.69	24.70	7.6

- e
- Tail Type
- N: No Tail
- C: Cup Tail
- W9: Square Tail for Wire Wrapping
Tail Length 9mm
- T5: Round Tail for Crimped Terminal
Tail Length 5mm
- S: Soldered Wire

- f
- Receptacle Base
- PB: Phosphor Bronze
- BR: Brass

- g
- Receptacle Plating
- Au: Gold

T SERIES LIST



Coding Rule:

ICT-T:**a-b-c-d-e-f**:g-h-i-j

Example:

ICT-T:**098-2050-0700-0450-LA-T5**:BC-Au-PB-Au

T Series	Dimensions	Materials	T Series	Dimensions	Materials
	a Barrel Diameter in mm	b Full Length in mm	c Board to Tip Length in mm	d Full Stroke in mm	e Tip Type See Tip Type Page
Recommended Pitch 1.70mm					
	0.98	20.50	07.00	04.50	f Tail Type
Recommended Pitch 2.00mm					
	1.34	27.00	10.00	06.00	N: No Tail
Recommended Pitch 2.50mm					
	1.83	36.00	16.00	12.00	C: Cup Tail
	2.00	43.00	16.00	06.00	W9: Square Tail for Wire Wrapping Tail Length 9mm
	2.00	50.00	23.00	06.00	T5: Round Tail for Crimped Terminal Tail Length 5mm
Recommended Pitch 0.80mm					
	2.33	38.00	16.00	10.50	S: Soldered Wire
Recommended Pitch 0.90mm					
	3.00	50.00	16.00	06.00	g Plunger Base
	3.00	54.00	20.00	06.00	BC: Beryllium Copper
	3.00	54.00	23.00	06.00	PB: Phosphor Bronze
Recommended Pitch 1.27mm					
	3.23	38.00	16.00	10.00	SK4: High Carbon Steel

h
Plunger Plating
Au: Gold
Rh: Rhodium
Ni: Nickel
NA: None

i
Barrel Base
PB: Phosphor Bronze
BR: Brass
POM: Polyoxymethylene

j
Barrel Plating
Au: Gold
NA: None

QUALITY MANAGEMENT

Quality System

ISO 9001: 2015

Quality Management System

ISO 14001: 2015

Environmental Management System

IATF 16949: 2016

Automotive Quality Management System

QC 080000

Hazardous Substance Process Management

Quality Assurance





C.C.P. CONTACT PROBES

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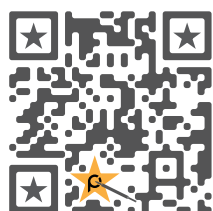
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